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APPLICANTS

Yasuo Yamagishi, Kawasaki, JAPAN;

Takeshi Shioga, Kawasaki, JAPAN;

John David Baniecki, Kawasaki, JAPAN; Kazuaki Kurihara, Kawasaki, JAPAN;

** CONTINUING DATA *****

** FOREIGN APPLICATIONS *****

JAPAN 2002-214476 07/23/2002

JAPAN 2003-020663 01/29/2003

JAPAN 2003-270360 07/02/2003

verified
g.m. H.

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Foreign Priority claimed 35 USC 119 (a-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance	STATE OR COUNTRY JAPAN	SHEETS DRAWING 15	TOTAL CLAIMS 27	INDEPENDENT CLAIMS 82
Verified and Acknowledged	<i>John D. Baniecki</i> Examiner's Signature Initials				

ADDRESS

23850
 ARMSTRONG, KRATZ, QUINTOS, HANSON & BROOKS, LLP
 1725 K STREET, NW
 SUITE 1000
 WASHINGTON, DC
 20006

TITLE

Probe card and testing method of semiconductor chip, capacitor and manufacturing method thereof.

FILING FEE	FEES: Authority has been given in Paper	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of
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